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Sı	Substitute for form 1449/PTO			Complete if Known		
				Application Number	10/788,741	
1	NFORMATIO	N DI	SCLOSURE	Filing Date	February 27, 2004	
•	STATEMENT	BY A	APPLICANT	First Named Inventor	Lee	
(Use as many sheets as necessary)				Art Unit	2813	
				Examiner Name	Nguyen, Tuan H.	
Sheet	1	of	2	Attorney Docket Number	ASC-012DV	

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S	STATEMENT BY APPLICANT			First Named Inventor	Lee	
				Art Unit	2813	
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